

Notice of References Cited	Application/Control No. 10/006,596	Applicant(s)/Patent Under Reexamination APUZZO ET AL.	
	Examiner CHAMELI C. DAS	Art Unit 2192	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,016,554	01-2000	Skrovan et al.	714/25
	C	US-5,651,111	07-1997	McKeeman et al.	714/38
	D	US-6,275,976	08-2001	Scandura, Joseph M.	717/120
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	TITLE: Automatic Test generation for linear digital systems with bi-level search using matrix transform methods, author: Roy et al, IEEE, 1992.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.